

Form PTO-1449 U.S. Department of Commerce
(REV. 2-82) Patent and Trademark OfficeAtty. Docket No.
036179/US/2-475387-30Serial No.
10/577,562**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**
(Use several sheets if necessary)Applicant(s)
Seok-Hyun YunFiling Date
April 27, 2006Confirmation No.
3634**U.S. PATENT DOCUMENTS**

*Exam. Init.	Document No.							Date	Name	Class	Subclass	Filing Date if Appropriate
	6	3	4	1	0	3	6	January 22, 2002	Tearney et al. ○○○○○			
	6	3	9	6	9	4	1	May 28, 2002	Bacus, James W. et al. ○○○○○			
200	5	0	1	8	2	0	1	January 27, 2005	De Boer, Johannes P. Et al ○○○○○			
	6	5	6	7	5	8	5	May 20, 2003	Martin et al ○○○○○			
	5	9	2	6	5	9	2	July 20, 1999	Martin et al. ○○○○○○○			
	7	2	6	7	4	9	4	September 11, 2007	Hongyu et al. ○○○○○○○			
	5	9	7	5	6	9	7	November 2, 1999	Podoleanu et al.			
	5	2	4	1	3	6	4	August 31, 1993	Kimura et al. ○○○○○○○ ○			
	5	9	1	0	8	3	9	June 8, 1999	Erskine et al ○○○○○○○ ○			
200	7	0	7	0	4	9	6	March 29, 2007	Gweon et al. ○○○○○○○ ○			
	4	8	2	7	9	0	7	May 9, 1989	Tashiro et al. ○○○○○○○ ○○			
	4	9	9	8	9	7	2	March 12, 1991	Chin et al. ○○○○○○○ ○			
	5	7	3	0	7	3	1	March 24, 1998	Mollenauer et al. ○○○○○○○ ○			
200	3	1	2	0	1	3	7	June 26, 2003	Pawluczyk et al ○○			

Examiner

Date Considered

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200	2	0	9	1	3	2	2	July 11, 2002	Chaiken et al. YY			
2005	0	1	6	5	3	0	3	July 28, 2005	Kleen Martin et al. YYY			
200	2	0	5	2	5	4	7	May 2, 2002	Toida Masamiro YYY			
200	4	0	0	2	6	5	0	January 1, 2004	Mandrusov Evgenia et al. YYY			
200	3	0	8	2	1	0	5	May 1, 2003	Fischman, Alan et al. YYY			
	5	3	0	4	1	7	3	April 19, 1994	Kittrell, Carter et al. YYY			
	7	3	3	6	3	6	6	February 26, 2008	Choma et al.			
	7	0	1	9	8	3	8	March 28, 2006	Izatt et al.			
	6	3	7	4	1	2	8	April 16, 2002	Toida et al.			
	6	4	7	7	4	0	3	November 5, 2002	Eguchi et al.			
	5	5	5	5	0	8	7	September 10, 1996	Miyagawa et al. YYYY			
200	5	0	5	7	7	5	6	March 17, 2005	Fang-Yen et al. YYYY			
200	5	0	3	5	2	9	5	February 17, 2005	Bouma et al.			
200	3	0	2	8	1	1	4	February 6, 2003	Casscells, III et al.			
200	3	0	9	7	0	4	8	May 22, 2003	Ryan et al.			

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200	4	0	5	4	2	6	8	March 18, 2004	Esnalciev et al.			
200	4	0	7	7	9	4	9	April 22, 2004	Blofgett et al.			
200	4	0	7	2	2	0	0	April 15, 2004	Rigler et al.			
200	6	1	4	6	3	3	9	July 6, 2006	Fujita et al.			
200	4	2	6	3	8	4	3	December 30, 2004	Knopp et al.			

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Document No.								Date	Country	Class	SubClass	Translator Yes No	
200	2	0	8	4	2	6	3	October 24, 2002	WIPO ΩΩΩΩΩ				
200	4	0	5	7	2	6	6	July 8, 2004	WIPO ΩΩΩΩΩ				
200	1	0	2	7	6	7	9	April 19, 2001	WIPO ΩΩΩΩΩΩ				
200	3	0	4	6	6	3	6	June 5, 2003	WIPO ΩΩΩΩΩΩ				
200	6	0	0	4	7	4	3	January 12, 2006	WIPOΩΩΩΩ ΩΩΩΩ				
	9	2	0	1	9	6	6	February 6, 1992	WIPO¥				
	6	0	7	3	4	0	5	April 25, 1985	Japan¥				
	5	5	0	9	4	1	7	November 22, 1993	Japan¥				
	2	7	3	8	3	4	3	August 30, 1995	France¥				
200	3	0	6	2	8	0	2	July 31, 2003	WIPO				

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	200	5	0	4	7	8	1	3	May 26, 2005	WIPO				
		2	2	9	8	0	5	4	August 21, 1996	Great Britain YYY				
	200	6	1	2	4	8	6	0	November 23, 2006	WIPO YYY				
		0	7	2	8	4	4	0	August 28, 1996	Europe				
	200	7	0	2	8	5	3	1	March 15, 2007	WIPO				
	199	8	0	4	8	8	4	6	November 5, 1998	WIPO				
	200	3	1	0	5	6	7	8	December 24, 2003	WIPO				
	200	6	0	3	9	0	9	1	April 13, 2006	WIPO				
	200	7	0	8	3	1	3	8	July 26, 2007	WIPO				
	200	6	0	5	9	1	0	9	June 8, 2006	WIPO				

~~QQQQ~~Reference cited in International Search Report and Written Opinion dated March 23, 2006 for International Application No. PCT/US2005/042408

~~QQQQ~~Reference cited in International Search Report and Written Opinion dated February 28, 2007 for International Application No. PCT/US2006/038277

~~QQQQ~~Reference cited in International Search Report and Written Opinion dated January 30, 2009 for International Application No. PCT/US2008/081834

~~QQQQ~~Reference cited in International Search Report and Written Opinion dated February 2, 2009 for International Application No. PCT/US2008/071786

~~QQQQ~~Reference cited in International Search Report and Written Opinion dated January 15, 2009 for International Application No. PCT/US2008/074863

~~QQQQ~~Reference cited in Office Action dated February 17, 2009 for U.S. Patent application no. 11/211,483

~~YYY~~Reference cited in Japanese Office Action dated December 2, 2008

~~YYY~~Reference cited in International Search Report and Written Opinion dated February 24, 2009 for PCT/US2008/076447

~~YYY~~Reference cited in European Official Communication dated February 12, 2008 for EP 07718117.0

~~YYY~~Reference cited in International Search Report and Written Opinion dated June 10, 2009 for PCT/US2008/075456

OTHER DOCUMENTS (including Author, Title Date, Pertinent Pages, Etc.)

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Copy of Notification Concerning Transmittal of Copy of International Preliminary Report on Patentability dated October 13, 2005 for PCT/US04/10152

Copy of International Search Report and Written Opinion dated March 23, 2006 for PCT/US2005/042408

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Copy of International Search Report and Written Opinion dated February 28, 2007 for International Application No. PCT/US2006/038277 ~~XXXXXXXXXX~~Copy of International Search Report and Written Opinion dated January 30, 2009 for International Application No. PCT/US2008/081834 ~~XXXXXXXXXX~~Copy of International Search Report and Written Opinion dated February 2, 2009 for International Application No. PCT/US2008/071786 ~~XXXXXXXXXX~~Bilenca A et al: "The Role of Amplitude and phase in Fluorescence Coherence Imaging: From Wide Field to Nanometer Depth Profiling". *Optics IEEE*, May 5, 2007 ~~XXXXXXXXXX~~Inoue, Yusuke et al: "Variable Phase-Contrast Fluorescence Spectrometry for Fluorescently Strained Cells", *Applied Physics Letters*, September 18, 2006 ~~XXXXXXXXXX~~Bernet, S et al: "Quantitative Imaging of Complex Samples by Spiral Phase Contrast Microscopy". *Optics Express*, May 9, 2006 ~~XXXXXXXXXX~~

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Barfuss et al (1989) "Modified Optical Frequency Domain Reflectometry with High spatial Resolution for Components of Integrated optic Systems", Journal of Lightwave Technology, IEEE Vol 7., No. 1

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Gelikono, V.M. et al. October 1, 2004 "Two-Wavelength Optical Coherence Tomography" Radio Physics and Quantum Electronics, Kluwer Academic Publishers-Consultants, Vol. 47, No. 10-1

4824-1162-7012\1

Examiner /Michael A. Lyons/

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